





ROSA and Solar Cell Module Combined Environments Test Plan

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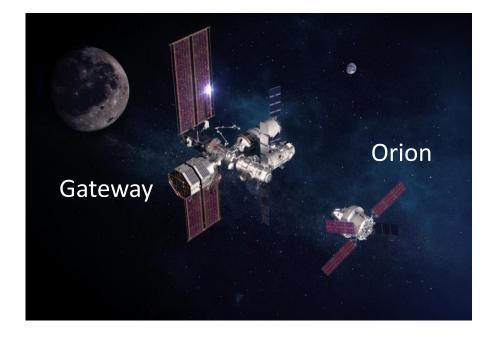


Background

- Maxar is developing advanced, lightweight, flexible Roll-out Solar Arrays (ROSA) for use on the Power and Propulsion Element (PPE) for Gateway
- Near Rectilinear Halo orbit (NRHO) planned for Gateway – moon centric



Credit: NASA iss052e002865



Credit: NASA/JSC 51670047958_9323e6ad71_h



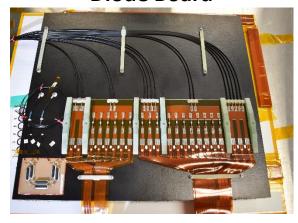


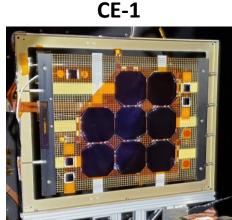


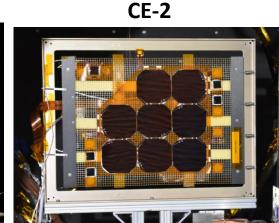
Test Coupons

- Design risk reduction through coupon testing
- 3 solar cell module coupons: Z4J cells with Qioptiq CMG coverglass with single layer MgF2 anti-reflective coating
- Diode Board: representing electrical current management at base of Photovoltaic Array (PVA) wing

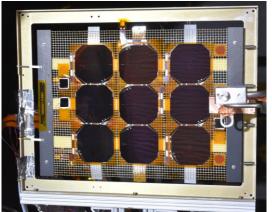
Diode Board







CE-4



Back



Picture Credits: NASA/MSFC/Todd Schneider

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Space Environments and Diagnostics

EOR = **Earth Orbit Raising**

Cumulative Space Environment Exposure				
Туре	EOR	EOR+5y	EOR+15y	
UV radiation in Equivalent Sun Hours (Front)	667	1333	2000	
1 MeV electrons in 10 ¹⁴ #/cm ² (Front&Back)	6.24	8.4	12.1	
40-50 keV protons in 10 ¹⁵ #/cm ² (F&B)	2.0	4.6	9.8	
580 eV xenon ions in 10 ¹⁹ #/cm ² cells (F&B)	1.35	1.4	1.5	
580 eV xenon ions in 10^{18} #/cm ² diode board (F)	8.43	8.75	9.37	
vacuum thermal cycling at +100 C to -183 C (F&B)	268	318	418	
electrostatic discharge (ESD) # arcs (F&B):	2	2	2	

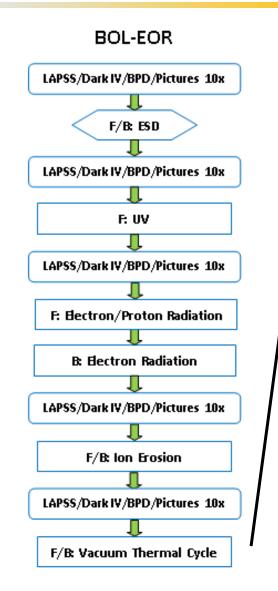
Diagnostics are preformed at Beginning of Life (BOL) and after each environment: 10x magnification picture, Large Area Pulsed Solar Simulator (LAPSS), Dark I-V, Bypass Diode, Forward Bias (FB) and Reverse Bias (RB) of each component of diode board

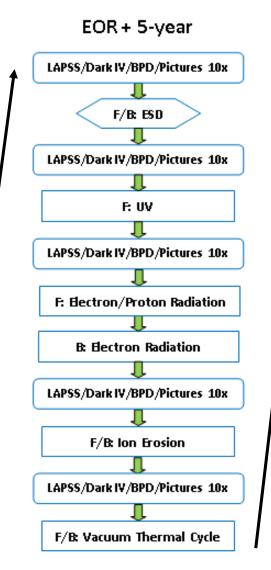


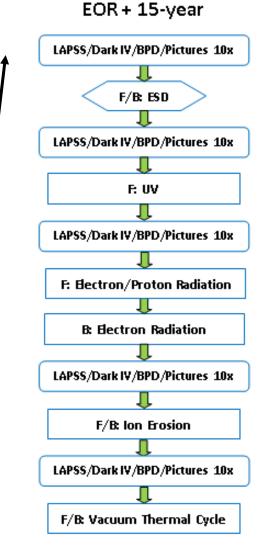




Test and Diagnostic Sequence







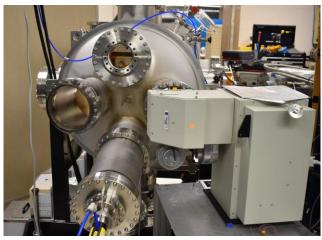




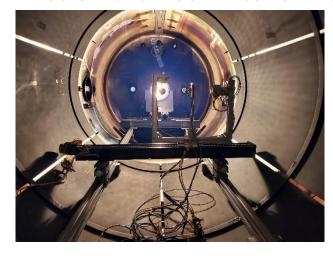


MSFC Environment Test Chambers

UV Test Chamber



Ion Erosion Chamber: interior view

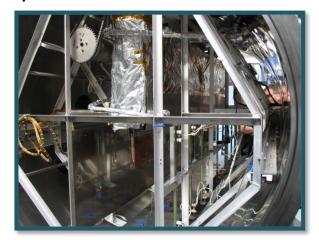


Picture credits: NASA/ Todd Schneider

Pelletron System: Electron and Proton Radiation



T/V chamber: interior view

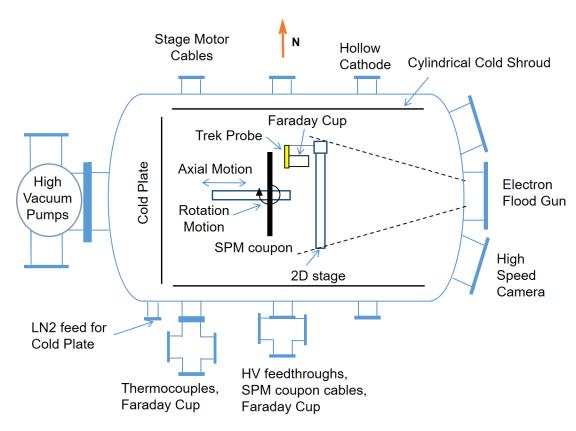


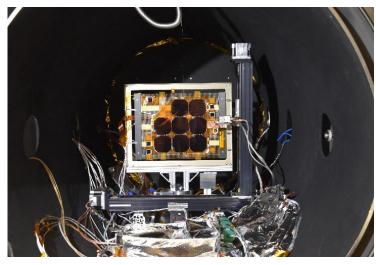






MSFC Electrostatic Discharge (ESD) Test Chamber





Picture credit: NASA/ Todd Schneider

New chamber allows upgraded capability: (1) colder (old -65C, new -110C); (2) rotation allows front and back testing in single pumpdown; (3) Fastec high-speed camera to capture arc picture





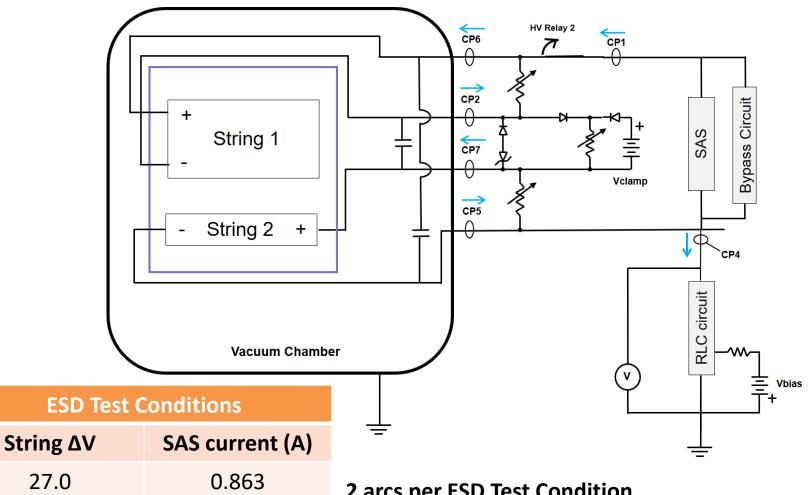
27.0

40.5

27.0



Solar Cell Module ESD Test Circuit



0.863

1.295

2 arcs per ESD Test Condition performed after each mission phase





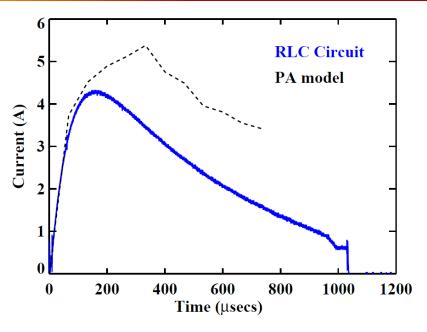


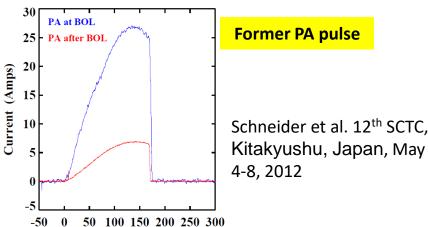
Updated Primary Arc Pulse

Primary Arc (PA) pulse

- Katz et al., Multicomponent Plasma Expansion Model for Arc Discharges on Large-Area Solar Arrays, JSR, Sep 2021
- Self consistent, spherical plasma expansion
- J_{the} limits arc peak current and duration

BOL Average Arc Inception Voltage				
Coupon	22 C	-105 C		
CE1	2.2 kV	1.9 kV		
CE2	1.6 kV	1.8 kV		
CE4	2.9 kV	2.3 kV		





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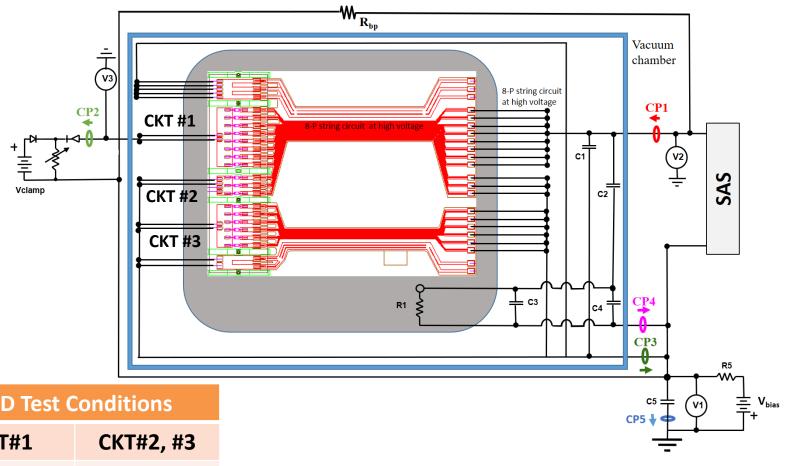
Time (microsec)







Diode Board ESD Test Circuit



ESD Test Conditions

CKT#1 100V, 6.9A 100V, 8.3A 120V, 6.9A

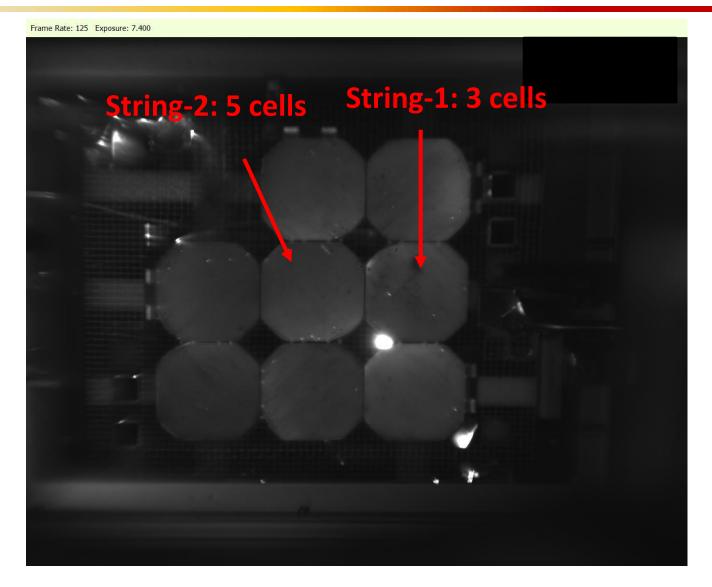
2 arcs per ESD Test Condition performed after each mission phase







CE2 BOL ESD Test: Example Arc Location



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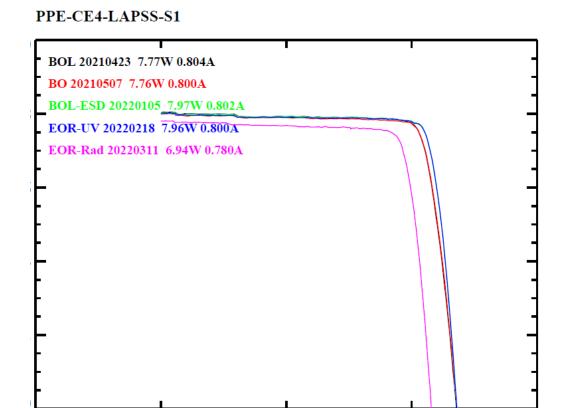






Degradation after EOR radiation phase

Δ% change from BOL		
String	Isc	
CE1-S1	-3.1	
CE1-S2	-4.1	
CE2-S1	-2.4	
CE2-S2	-2.4	
CE4-S1	-3.0	
CE4-S2	-3.0	
CE4-S3	-3.2	



- ~ 52% of EOL cumulative electron radiation occurs in EOR
- ~ 20% of EOL cumulative proton radiation occurs in EOR

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Summary

- PPE ROSA risk reduction test campaign well underway
 - All solar cell module coupons have completed EOR radiation and are in EOR ion erosion test
 - Diode board in BOL ESD test
- Completion of test program expected ~ May 2023

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